

Notice of References Cited	Application/Control No. 10/676,728	Applicant(s)/Patent Under Reexamination BEDELL ET AL.	
	Examiner A. Dexter Tugbang	Art Unit 3729	Page 1 of 1

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*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
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*	C	US-6,278,591	08-2001	Chang et al.	360/126 x
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*	F	US-6,779,249	08-2004	Santini, Hugo Alberto Emilio	29/603.15 x
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	L	US-			
	M	US-			

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NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
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